

## Search Notes



## Application/Control No.

10/688,976

## Examiner

Henry K. Choe

## Applicant(s)/Patent under Reexamination

KONDO ET AL.

## Art Unit

2817

## SEARCHED

Class	Subclass	Date	Examiner
330	295	~1/1/05	H.C.
"	288	"	"
"	124R	"	"
"	296	~1/2/05	"
"	285	"	"
323	315	"	"
"	316	~1/23/05	"

SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Tool search (East)	~1/3/05	H.C.
NPL (IEEE)	"	"

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner